•	Application No.	Applicant(s)
Notice of Allowability	10/075,656	RICHTER, DETLEV
	Examiner	Art Unit
	John J. Tabone, Jr.	2117
The MAILING DATE of this communication app All claims being allowable, PROSECUTION ON THE MERITS IS herewith (or previously mailed), a Notice of Allowance (PTOL-85 NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT F of the Office or upon petition by the applicant. See 37 CFR 1.31	S (OR REMAINS) CLOSED in this i) or other appropriate communica RIGHTS. This application is subje	application. If not included tion will be mailed in due course. THIS
1. X This communication is responsive to arguments filed 04/1	<u>11/2007</u> .	
2. 🗵 The allowed claim(s) is/are <u>1-13</u> .		
 3. Acknowledgment is made of a claim for foreign priority unally a) All b) Some* c) None of the: 1. Certified copies of the priority documents have 2. Certified copies of the priority documents have 	re been received. re been received in Application No)
3. Copies of the certified copies of the priority do	ocuments have been received in the	his national stage application from the
International Bureau (PCT Rule 17.2(a)). * Certified copies not received:		
Applicant has THREE MONTHS FROM THE "MAILING DATE" noted below. Failure to timely comply will result in ABANDON! THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.		ply complying with the requirements
4. A SUBSTITUTE OATH OR DECLARATION must be subminFORMAL PATENT APPLICATION (PTO-152) which give	mitted. Note the attached EXAMIN ves reason(s) why the oath or dec	IER'S AMENDMENT or NOTICE OF laration is deficient.
5. CORRECTED DRAWINGS (as "replacement sheets") mu	ust be submitted.	
(a) 🔲 including changes required by the Notice of Draftsper	rson's Patent Drawing Review (P	TO-948) attached
1) 🗌 hereto or 2) 🗍 to Paper No./Mail Date	_ ·	
(b) including changes required by the attached Examiner Paper No./Mail Date	r's Amendment / Comment or in th	ne Office action of
Identifying indicia such as the application number (see 37 CFR each sheet. Replacement sheet(s) should be labeled as such in		
 DEPOSIT OF and/or INFORMATION about the deposit attached Examiner's comment regarding REQUIREMENT 		
Attachment(s) 1. ☐ Notice of References Cited (PTO-892)	5 🗆 Notice of Inform	al Patant Application
 Notice of References Cited (FTO-692) Dotice of Draftperson's Patent Drawing Review (PTO-948) 	5. ☐ Notice of Information 6. ☐ Interview Summ	, ,
3. ☐ Information Disclosure Statements (PTO/SB/08),	Paper No./Mail 7. ⊠ Examiner's Ame	Date
Paper No./Mail Date		
 Examiner's Comment Regarding Requirement for Deposit of Biological Material 	8. ⊠ Examiner's State 9. □ Other	ement of Reasons for Allowance
A	9. [] Other	
P	GUY LAMARRE RIMARY EXAMINER	John J. Tabone, Jr. Examiner AU 2117

DETAILED ACTION

1. Claims 1-13 are currently pending in the application and have been examined.

EXAMINER'S AMENDMENT

2. An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it MUST be submitted no later than the payment of the issue fee.

Authorization for this examiner's amendment was given in a telephone interview with Attorney Kerry P. Sisselman on 06/21/2007.

The application has been amended as follows:

Claim 1, line 10: Change "a first circuit" to "first circuits".

Response to Arguments

3. Applicant's arguments, filed 04/11/2007, with respect to claims 1 and 7 have been fully considered and are persuasive. The Non-Final Rejection of 01/11/2007 has been withdrawn.

Allowable Subject Matter

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4. Claims 1-13 are allowed.

The following is an Examiner's Statement of Reasons for Allowance:

The present invention relates to a semiconductor module with a plurality of interface circuits and a configuration for the self-test of interface circuits. The application furthermore relates to a method for the self-test of interface circuits of such a semiconductor module.

The claimed invention as set forth in **claim 1** recites features such as:

A semiconductor module with a configuration for the self-test of a plurality of bidirectionally operating interface circuits, comprising:

first and second equally sized groups of interface circuits, wherein each interface circuit of said first group is assigned exactly one interface circuit of said second group;

a respective electrical connection of the interface circuits of said first and second groups to outside of the semiconductor module, for enabling a self-test;

first circuits connected to said first group and serving to generate test signals to be multiplexed in and output via said interface circuits of said first group;

a second circuit connected to said second group for receiving and processing test signals received via said interface circuits of Said second group; and

a respective separate voltage supply for said first and second groups of interface circuits.

The Examiner agrees with the Applicant's arguments, filed 04/11/2007, with regard to the allowable features in view of the arts of record, namely **Bates et al.** (US-

6477674); therefore, the Examiner favors the allowance of **claims 1-13**. Any comments considered necessary by applicant must be submitted no later than the payment of the Issue Fee and, to avoid processing delays, should preferably accompany the Issue Fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to John J. Tabone, Jr. whose telephone number is (571) 272-3827. The examiner can normally be reached on M-F.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, JACQUES H. LOUIS JACQUES can be reached on (571) 272-6962. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

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Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

John J. Tabone, Jr. 6/21/07

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